

<b>Search Notes</b>  	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10032567	CHOI ET AL.
	<b>Examiner</b> Kendall, Chuck O	<b>Art Unit</b> 2192

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
East Search (USPAT, USPGPUB, IBM, DERWENT, JPO, EPO, see search history print out)	12/15/06	Ck
717 /124-131 (text search only see search history printout)	12/15/06	Ck
714/38-48 (text search only see search history printout)	12/15/06	Ck
717/144(text search only see search history printout)	12/15/06	Ck
IEEE search	12/15/06	Ck

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
717	127,131	12/16/06	Ck
714	38, 48	12/16/06	Ck
717	144	12/16/06	Ck